

**Notice of References Cited**

Application/Control No.

09/810,828

Applicant(s)/Patent Under  
Reexamination  
ZARRABIAN ET AL.

Examiner

Thomas R Artman

Art Unit

2882

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**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
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	C	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Takashashi, Haruo. "Temperature stability of thin-film narrow-bandpass filters produced by ion-assisted deposition." <input type="checkbox"/> Applied Optics, Vol. 34, No. 4, Feb.1, 1995, pp.667-675
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.